

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant

Philip LeBlanc

Serial No.

10/626,309

Filed

July 24, 2003

For

FIBER ARRAY INTERFEROMETER FOR

INSPECTING GLASS SHEETS

MODIFIED 1449 FORM

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FORM PTO-1449 (MODIFIED)

LIST OF PATENTS AND **PUBLICATIONS** OR APPLICANTS INFORMATION
DISCLOSURE STATEMENT

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SP03-089

10/626,309

APPLICANT: Philip Robert LeBlanc, et al.

ADE			FIL	ING DATE July 24, 2	2003	GROUP: 2	2877			
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